

Form PTO-1449

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICEATTY. DOCKET NO.
MI22-1284SERIAL NO. *Unknown*
09/421,625LIST OF ART CITED BY APPLICANT
(Use several sheets if necessary)APPLICANT
Eugene P. MarshFILING DATE
Filed herewith 01/19/99GROUP 2811
*Unknown*10559 U.S. P.T.O.
09/421,625

10/19/99

U.S. PATENT DOCUMENTS

*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
<u>Vu</u>	AA	5,639,685	6/17/97	Zahurak et. al.	438	658	-
<u>Vu</u>	AB	5,917,213	6/29/99	Iyer et. al.	257	309	-
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						

FOREIGN PATENT DOCUMENTS

		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
<u>Vu</u>	AL	5-67730	3/19/93	Japan	-	-		✓
	AM							
	AN							
	AO							
	AP							

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

<u>Vu</u>	AR	Ju-Hong Kwan et al.; "Characterization of Pt Thin Films Deposited by Metallorganic Chemical Vapor Deposition for Ferroelectric Bottom Electrodes"; J. Electrochem. Soc., Vol. 144, No. 8, August 1997; pp. 2848-2854
<u>Vu</u>	AS	M. Ino et al.; "Rugged surface polycrystalline silicon film deposition and its application in a stacked dynamic random access memory capacitor electrode"; J. Vac. Sci. Technol. B 14(2), March/April 1996; pp. 751-756
	AT	

EXAMINER

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DATE CONSIDERED

03/20/01

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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APPLICANT
Micron Technology, Inc.FILING DATE
October 19, 1999GROUP
2811

U.S. PATENT DOCUMENTS

*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
<u>Vu</u>	AA	3,856,709	12/24/74	Porta et al.	502	178	—
	AB	3,975,304	8/17/76	della Porta et al.	502	178	
	AC	4,341,662	7/27/82	Pfefferle	502	201	
	AD	4,425,261	1/10/84	Stenius et al.	502	339	
	AE	4,431,750	2/14/84	McGinnis et al.	502	329	
	AF	4,714,693	12/22/87	Targos	502	261	
	AG	4,719,442	1/12/88	Bohara et al.	338	25	
	AH	5,053,917	10/1/91	Miyasaka et al.	361	321.5	
	AI	5,208,479	5/4/93	Mathews et al.	257	534	
	AJ	5,330,700	7/19/94	Soukup et al.	419	2	
<u>Vu</u>	AK	5,525,570	6/11/96	Chakraborty et al.	502	326	—

FOREIGN PATENT DOCUMENTS

		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
<u>Vu</u>	AL	0 415 751 A1	3/6/91	EPO	—	—	✓	
<u>Vu</u>	AM	0 855 738 A2	7/29/93 4/15/97	EPO	—	—	✓	
<u>Vu</u>	AN	9-82666	3/28/97	Japan	—	—		✓
	AO							
	AP							

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

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LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)									
APPLICANT Micron Technology, Inc.						FILING DATE October 19, 1999		GROUP 2811	
U.S. PATENT DOCUMENTS									
*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate			
Vu	AA 5,783,716	7/21/98	Baum et al.	556	136	—			
	AB								
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	Document Number	Date	Country	Class	Subclass	Translation			
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	AR		<div style="border: 1px solid black; width: 100%; height: 100%; position: relative;"> <div style="position: absolute; top: 0; right: 0; bottom: 0; left: 0; background: linear-gradient(to top right, transparent 49%, black 49%, black 51%, transparent 51%); background-size: 100% 100%;"></div> </div>						
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				FILING DATE October 19, 1999		GROUP 2811		
U.S. PATENT DOCUMENTS								
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
<u>V_u</u>	AA	5,874,364	02/99	Nakabayashi et al.	438	738	-	
<u>V_u</u>	AB	6,033,953	03/00	Aoki et al.	438	255	-	
<u>V_u</u>	AC	5,320,978	06/94	Hsu	438	606	-	
<u>V_u</u>	AD	5,763,286	06/98	Figura et al.	438	255	-	
<u>V_u</u>	AE	5,796,648	08/98	Kawakubo et al.	365	145	-	
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